

Characterization of small pitch 3D sensors from CNM

Monday 5 June 2017 11:20 (20 minutes)

Silicon pixels of area 25x100 and 50x50 square microns, fabricated at CNM using double sided 3D technology on 230 um thick wafers, are characterized using a Sr90 radioactive source and in a pion/proton test beam at the CERN SPS. Results are shown both for non-irradiated sensors and for sensors irradiated with protons at the CERN PS.

Author: CURRAS RIVERA, Esteban (Universidad de Cantabria (ES))

Presenter: CURRAS RIVERA, Esteban (Universidad de Cantabria (ES))

Session Classification: Pixel and strip sensors